

SEP 19 2003
U.S. PATENT AND TRADEMARK OFFICE
RECEIVED

LIST OF REFERENCES CITED BY APPLICANT
(Use several sheets if necessary)

ATTY DOCKET NO	APPLICATION NO
9840-0068-999	10,076,296 <i>RECE</i>
APPLICANT	
Conant et al.	<i>SEP 25 2003</i>
FILING DATE	GROUP
February 13, 2002	1765 <i>TC 7/6</i>

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

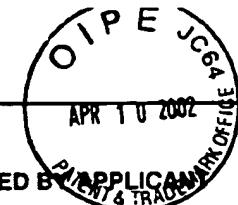
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES <i>NO</i>

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>AKS</i>	Conant et al. "Cyclic Fatigue Testing of Surface-Micromachined Thermal Actuators", 1998 ASME International Mechanical Engineering Congress and Exposition, Nov. 15-20, 1998, Anaheim, CA DSC-Vol. 66, pp. 273-277
	Cotton et al., "Wide-angle geocoronal telescope: a He-II 304-A plasmaspheric imager", Optical Engineering, December 1993, Vol. 32 No. 12, pages 3170-3173
	Hart et al., "Stroboscopic phase-shifting interferometry for dynamic characterization of optical MEMS", 18th Congress of the International Commission for Optics, ICO XVIII August 2-6, 1999, San Francisco, CA USA, Optics for the Next Millennium, Technical Digest SPIE Volume 3749, pgs 468-469
	Hoon et al, "A Model for SIMOX Buried-Oxide High-Field Conduction", IEEE Transactions on Electron Devices, Vol. 43, No. 11, November 1996
	Hyodo et al., "An HDR System Hydraulics Model and Detailed Analysis of the 1991 Circulation Test at the Hijiori HDR Site, Japan", Geothermal Resources Council Transactions, Vol. 198, October 1995, pgs 263-268
	Hyodo et al., "An HDR System Hydraulics Model and Analysis of the 1995 Preliminary Circulation Test at the Hijiori HDR Site of the NEDO Project, Japan", Twentieth Stanford Workshop on Geothermal Reservoir Engineering, pgs 23-24
	Wright et al., "Hydraulic Fracture Orientation and Production/Injection Induced Reservoir Stress Changes in Diatomite Waterfloods", Society of Petroleum Engineers, pages 139-151
	Wright et al., "Reorientation of propped fracture treatments", Eurock '97 © 1994 Balkema, Rotterdam, ISBN 90 5410 502 X, pages 417-424
	Yap et al., "Conduction Mechanisms Through Simox Buried Oxide", in Proceedings of 1993 IEEE International SOI Conference, Palm Springs, CA, USA, October 5-7, 1993, pp. 32-33
	Yap et al., "A Model for High-Field Conduction In Simox Buried Oxides", in Proceedings of 1994 IEEE International SOI Conference, Nantucket, MA, USA, October 3-6, 1994, pp. 93-94
	Yao and MacDonald, "Single Crystal Silicon Supported Thin Film Micromirrors for Optical Applications", Opt. Eng., 36(5):1408-1413, May 1997
	Yeh et al., "Integrated Polysilicon and DRIE Bulk Silicon Micromachining for an Electrostatic Torsional Actuator", J. Microelectromechanical Systems, 8(4):456-465, Dec. 1999
	Yeh et al. "Mechanical Digital-To-Analog Converters", proc. Transducers '99, Sendai, Japan, June 1999, pp. 998-1001
<i>↓</i>	Voon et al. "Use of High-Field Electrical Testing for SIMOX BOX Metrology", in Proceedings of 1995 IEEE International SOI Conference, Tucson, AZ, USA, October 3-5, 1995, pp. 146-147

EXAMINER	<i>Anita K. Holmes</i>	DATE CONSIDERED	<i>12/15/03</i>
----------	------------------------	-----------------	-----------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



APR 10 2002

LIST OF REFERENCES CITED BY APPLICANT
(Use several sheets if necessary)

ATTY/DEALER

APPL. ATT'D.

9840-0068-999

10/076.296

APPLICANT

Conant et al.

FLN/SCATE

February 13, 2002

GROUP

1765

To be assigned

U. S. PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FLN/SCATE PAPER OR DRAFT
AC	AA	6,201,629	3/13/01	McClelland et al.			
AC	AB	5,959,760	9/28/99	Yamada et al.	JUL 26 2002 TC 1700		

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
AC	AC	PCT/US01/15514	5/14/01	PCT Int'l Search Report			YES NO

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

AC	AD	Kam Y. Lau, "Microscanner Raster-scanning Display: A Spyglass for the Future", Optics & Photonic News, May 1999 Vol.. 10 No. 5, pages 47-50, 84
	AE	Nee et al. "Stretched-Film Micromirrors For Improved Optical Flatness", IEEE MEMS 2000 Conference, January 23-27 2000, Miyazaki, Japan
	AF	Conant et al. "Robustness and Reliability of Micromachined Scanning Mirrors", MOEMS 1999, Mainz Germany, August 1999
	AG	Hagelin et al. "Integrated Micromachined Scanning Display Systems", presented at 18 th Congress of the International Commission for Optics, San Francisco, CA, August 1999
	AH	Conant et al. "A Raster-Scanning Full-Motion Video Display Using Polysilicon Micromachined Mirrors", proc. Transducers '99, Sendai, Japan, June 1999, pp. 376-379
	AI	Hart et al. "Time-Resolved Measurement of Optical Mems Using Stroboscopic Interferometry", proc. Transducers '99, Sendai, Japan, June 1999, pp. 470-473
	AJ	Nee et al. "Scanning Blazed-Grating for High-Resolution Spectroscopy", 1998 Workshop for Solid State Sensors and Actuators (HH '98) Late News Poster Session Supplemental Digest, Hilton Head Island, June 8-11, 1998, pgs. 9-10
	AK	Kiang et al. "Surface-Micromachined Diffraction Gratings for Scanning Spectroscopic Application", proc. Transducers '99, Sendai, Japan, June 1999, pp. 998-1001
	AL	Nee et al. "Lightweight, Optically Flat Micromirrors for Fast Beam Steering", IEEE/LEOS Optical MEMS 2000, Kauai, Hawaii, August 21-24, 2000
AC	AM	Conant et al. "A Flat High-Frequency Scanning Micromirror", 2000 Workshop for Solid State Sensors and Actuators (HH2000), Hilton Head Island, SC, USA, June 4-8, 2000, pp. 6-9, Digest of Technical Papers

EXAMINER *Conant*

DATE CONSIDERED

6/16/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609: Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.